# Elastic and inelastic resonance in an electron doped cuprate superconductor

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We expanded our resonant elastic X-ray scattering data set for the copper K-edge of  $Nd_{2-x}Ce_xCuO_4$  (x=14%), and acquired resonant inelastic X-ray scattering data for a comparison of the two types of resonant signal.

Keywords: x-ray scattering, k-edge resonance

### 1. Purpose

The relationship between elastic and inelastic resonant enhancement has not been extensively investigated, and may help in addressing open questions regarding the K-edge resonant scattering process in cuprates. The purpose of this experiment was to enlarge our RIXS and REXS data sets on  $Nd_{2-x}Ce_xCuO_4$ , so that RIXS and REXS can be compared for the first time on an electron-doped cuprate.

#### 2. Method

We measured total fluorescence yield, RIXS and REXS incident energy profiles with scattering wavevectors in the [001] plane. Because of limitations inherent to the REXS technique, all data were measured using the RIXS spectrometer in 90° scattering geometry, with momentum transfer (Q) wavevector near the Brillouin zone boundary.

## 3. Result

The RIXS profile near the Mott gap was successfully measured for comparison with elastic resonance in the [001] plane scattering geometry. Features attributed to the well screened resonance shifted to lower energies as a result of electron doping.

### 4. Conclusion

Incident energy profiles for RIXS and REXS were successfully measured for an electron doped system (Nd<sub>2-x</sub>Ce<sub>x</sub>CuO<sub>4</sub>), providing an initial basis for comparing the two techniques.

### 5. Reference